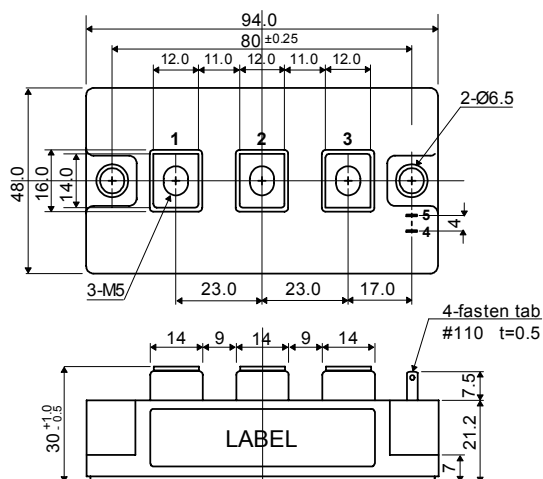
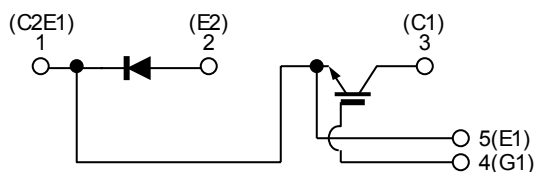


□ 回路図 : *CIRCUIT*□ 外形寸法図 : *OUTLINE DRAWING*

Dimension: [mm]

□ 最大定格 : *MAXIMUM RATINGS* ($T_c = 25^\circ\text{C}$)

Item		Symbol	Rated Value	Unit
コレクタ・エミッタ間電圧 Collector-Emitter Voltage		V_{CES}	1, 200	V
ゲート・エミッタ間電圧 Gate-Emitter Voltage		V_{GES}	± 20	V
コレクタ電流 Collector Current	DC	I_C	200	A
	1 ms	I_{CP}	400	
コレクタ損失 Collector Power Dissipation		P_C	960	W
接合温度 Junction Temperature Range		T_j	$-40 \sim +150$	$^\circ\text{C}$
保存温度 Storage Temperature Range		T_{stg}	$-40 \sim +125$	$^\circ\text{C}$
絶縁耐圧 (Terminal to Base AC, 1 minute) Isolation Voltage		V_{ISO}	2,500	$V_{(RMS)}$
締め付けトルク Mounting Torque	Module Base to Heatsink	F_{tor}	3 (30.6)	$\text{N} \cdot \text{m}$ ($\text{kgf} \cdot \text{cm}$)
	Busbar to Main Terminal		2 (20.4)	

□ 電気的特性 : *ELECTRICAL CHARACTERISTICS* ($T_c = 25^\circ\text{C}$)

Characteristic		Symbol	Test Condition	Min.	Typ.	Max.	Unit
コレクタ遮断電流 Collector-Emitter Cut-Off Current		I_{CES}	$V_{CE} = 1200\text{V}, V_{GE} = 0\text{V}$	—	—	4.0	mA
ゲート漏れ電流 Gate-Emitter Leakage Current		I_{GES}	$V_{GE} = \pm 20\text{V}, V_{CE} = 0\text{V}$	—	—	1.0	μA
コレクタ・エミッタ間飽和電圧 Collector-Emitter Saturation Voltage		$V_{CE(sat)}$	$I_C = 200\text{A}, V_{GE} = 15\text{V}$	—	1.9	2.4	V
ゲートしきい値電圧 Gate-Emitter Threshold Voltage		$V_{GE(th)}$	$V_{CE} = 5\text{V}, I_C = 200\text{mA}$	4.0	—	8.0	V
入力容量 Input Capacitance		C_{ies}	$V_{CE} = 10\text{V}, V_{GE} = 0\text{V}, f = 1\text{MHz}$	—	16,600	—	pF
スイッチング時間 Switching Time	上昇時間 Rise Time	t_r	$V_{CC} = 600\text{V}$ $R_L = 3\Omega$ $R_G = 2\Omega$ $V_{GE} = \pm 15\text{V}$	—	0.25	0.45	μs
	ターンオン時間 Turn-on Time	t_{on}		—	0.40	0.70	
	下降時間 Fall Time	t_f		—	0.25	0.35	
	ターンオフ時間 Turn-off Time	t_{off}		—	0.80	1.10	

□ フリーホイーリングダイオードの特性 : *FREE WHEELING DIODE RATINGS & CHARACTERISTICS* ($T_c = 25^\circ\text{C}$)

I t e m		S y m b o l	R a t e d V a l u e			U n i t
順電流 Forward Current	DC	I _F	200			A
	1 m s	I _{FM}	400			

C h a r a c t e r i s t i c		S y m b o l	T e s t C o n d i t i o n	M i n .	T y p .	M a x .	U n i t
順電圧 Peak Forward Voltage		V _F	I _F = 200A, V _{GE} = 0V	—	1.9	2.4	V
逆回復時間 Reverse Recovery Time		t _{rr}	I _F = 200A, V _{GE} = -10V di/dt = 400A/μs	—	0.2	0.3	μs

□ 熱的特性 : *THERMAL CHARACTERISTICS*

Characteristic		Symbol	Test Condition	Min.	Typ.	Max.	Unit
熱抵抗 Thermal Impedance	IGBT	$R_{th(j-c)}$	Junction to Case	—	—	0.125	$^\circ\text{C}/\text{W}$
	Diode			—	—	0.24	

Fig.1- Output Characteristics (Typical)

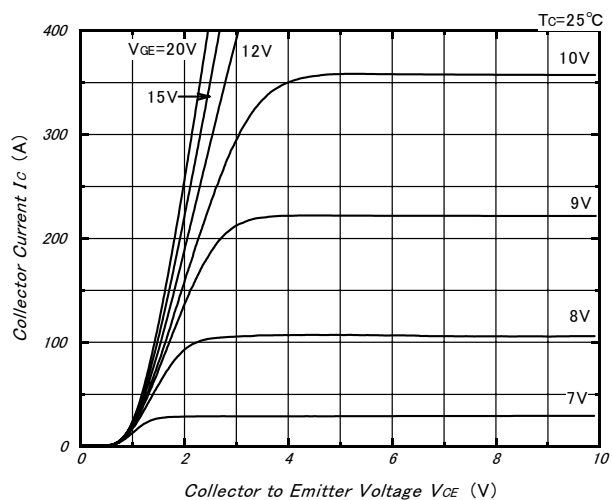


Fig.2- Collector to Emitter On Voltage vs. Gate to Emitter Voltage (Typical)

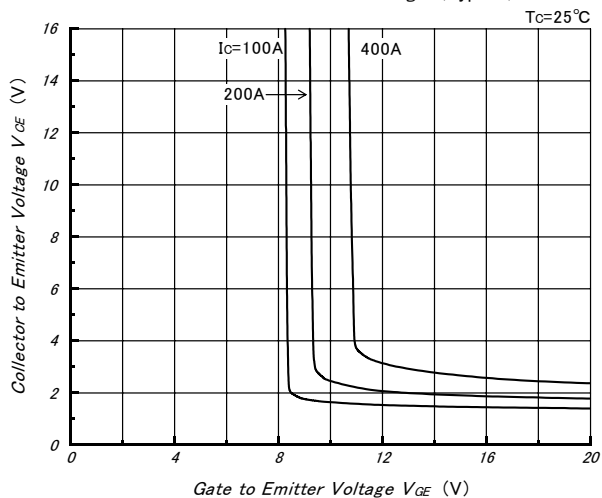


Fig.3- Collector to Emitter On Voltage vs. Gate to Emitter Voltage (Typical)

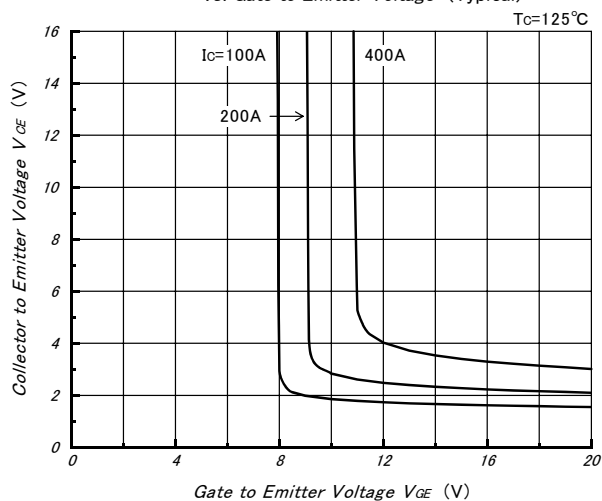


Fig.4- Gate Charge vs. Collector to Emitter Voltage (Typical)

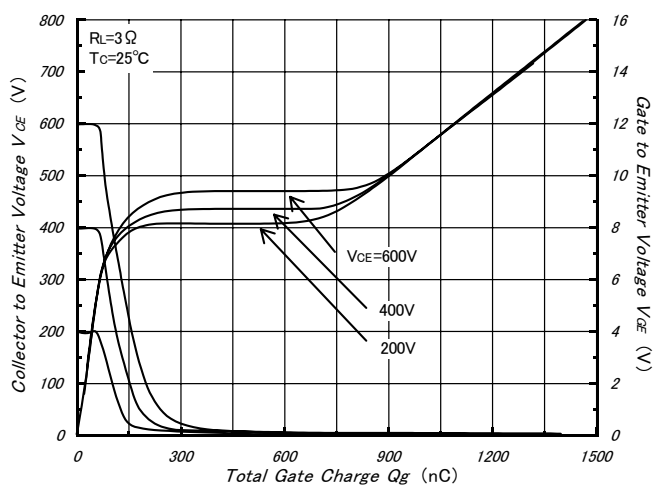


Fig.5- Capacitance vs. Collector to Emitter Voltage (Typical)

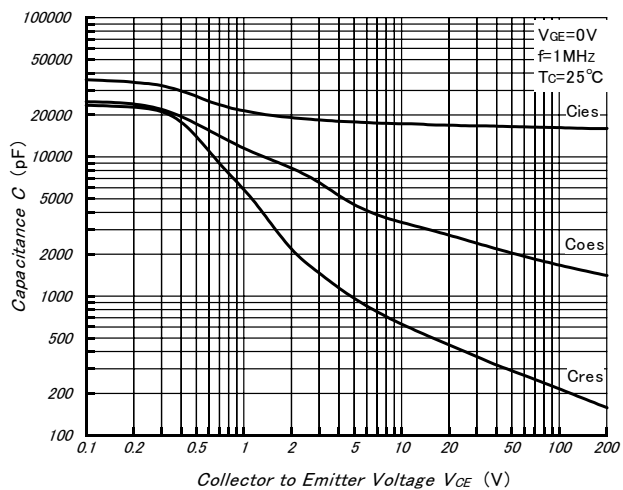


Fig.6- Collector Current vs. Switching Time (Typical)

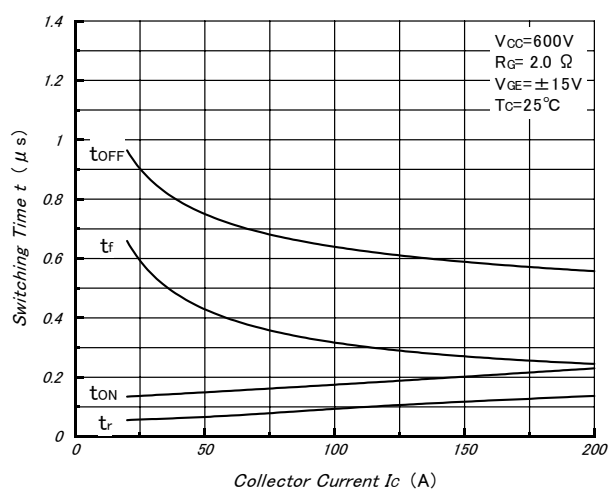


Fig.7- Series Gate Impedance vs. Switching Time (Typical)

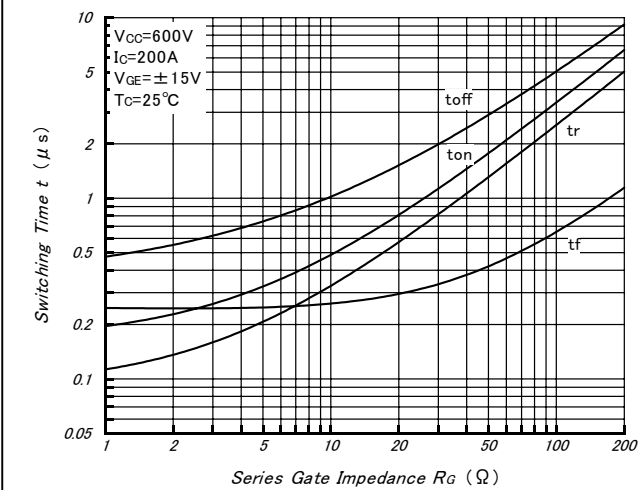


Fig.8- Forward Characteristics of Free Wheeling Diode (Typical)

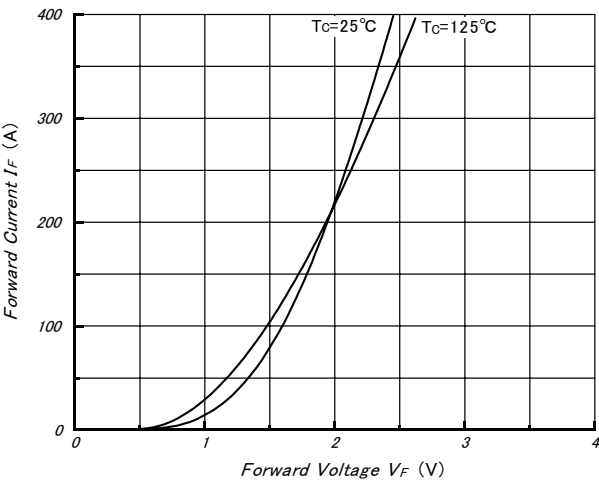


Fig.9- Reverse Recovery Characteristics (Typical)

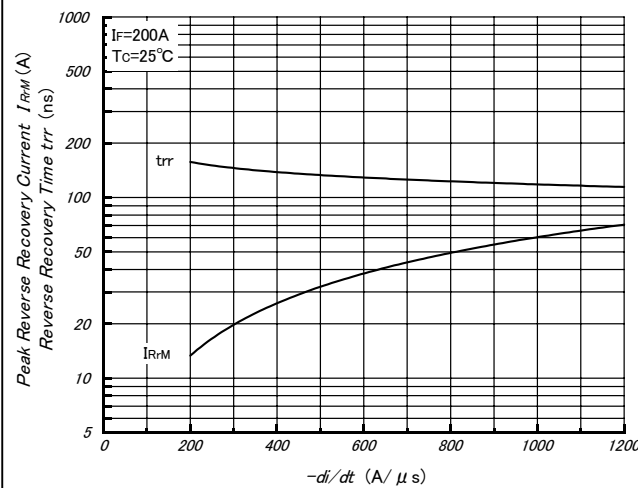


Fig.10- Reverse Bias Safe Operating Area

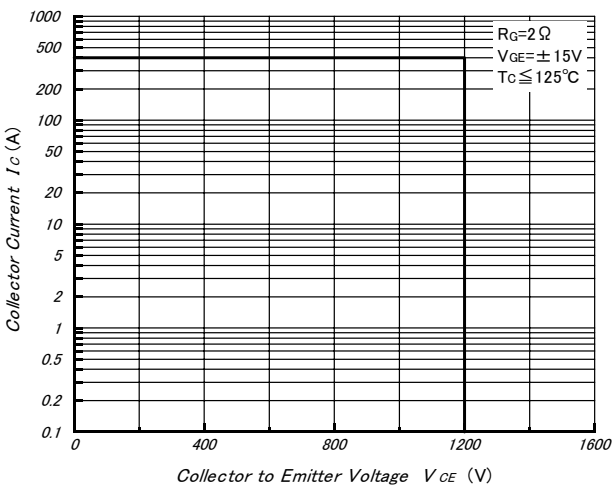


Fig.11- Transient Thermal Impedance

